

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 *     Zvector E7 instruction tests for VRR-c encoded:
				5 *
				6 *     E7B4 VGFM   - VECTOR GALOIS FIELD MULTIPLY SUM
				7 *
				8 *             James Wekel July 2024
				9 *****
				11 *****
				12 *
				13 *             basic instruction tests
				14 *
				15 *****
				16 *     This program tests proper functioning of the z/arch E7 VRR-c
				17 *     VECTOR GALOIS FIELD MULTIPLY SUM instruction.
				18 *     Exceptions are not tested.
				19 *
				20 *     PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 *     obvious coding errors.  None of the tests are thorough.  They are
				22 *     NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 *     *Testcase zvector-e7-02-VGFM  VECTOR E7 VRR-c instructions
				27 *     *
				28 *     *     Zvector E7 instruction tests for VRR-c encoded:
				29 *     *
				30 *     *     E7B4 VGFM   - VECTOR GALOIS FIELD MULTIPLY SUM
				31 *     *
				32 *     *     # -----
				33 *     *     #     This tests only the basic function of the instruction.
				34 *     *     #     Exceptions are NOT tested.
				35 *     *     # -----
				36 *     *
				37 *     mainsize       2
				38 *     numcpu         1
				39 *     sysclear
				40 *     archlvl        z/Arch
				41 *     *
				42 *     loadcore       "\$(testpath)/zvector-e7-02-VGFM core" 0x0
				43 *     *
				44 *     diag8cmd       enable     # (needed for messages to Hercules console)
				45 *     runtest        2
				46 *     diag8cmd       disable    # (reset back to default)
				47 *     *
				48 *     *Done
				49 *     *
				50 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				52 *****
				53 * FCHECK Macro - Is a Facility Bit set?
				54 *
				55 * If the facility bit is NOT set, an message is issued and
				56 * the test is skipped.
				57 *
				58 * Fcheck uses R0, R1 and R2
				59 *
				60 * eg. FCHECK 134, 'vector-packed-decimal'
				61 *****
				62 MACRO
				63 FCHECK &BITNO, &NOTSETMSG
				64 . * &BITNO : facility bit number to check
				65 . * &NOTSETMSG : 'facility name'
				66 LCLA &FBBYTE Facility bit in Byte
				67 LCLA &FBBIT Facility bit within Byte
				68
				69 LCLA &L(8)
				70 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				71
				72 &FBBYTE SETA &BITNO/8
				73 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				74 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				75
				76 B X&SYSNDX
				77 * Fcheck data area
				78 * skip messgae
				79 SKT&SYSNDX DC C' Skipping tests: '
				80 DC C&NOTSETMSG
				81 DC C' (bit &BITNO) is not installed.'
				82 SKL&SYSNDX EQU *-SKT&SYSNDX
				83 * facility bits
				84 DS FD gap
				85 FB&SYSNDX DS 4FD
				86 DS FD gap
				87 *
				88 X&SYSNDX EQU *
				89 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				90 STFLE FB&SYSNDX get facility bits
				91
				92 XGR R0, R0
				93 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				94 N R0, =F' &FBBIT' is bit set?
				95 BNZ XC&SYSNDX
				96 *
				97 * facility bit not set, issue message and exit
				98 *
				99 LA R0, SKL&SYSNDX message length
				100 LA R1, SKT&SYSNDX message address
				101 BAL R2, MSG
				102
				103 B EOJ
				104 XC&SYSNDX EQU *
				105 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				107	*****
				108	*            Low core PSWs
				109	*****
00000000		00000000	0000181F	110	ZVE7TST    START 0
		00000000		111	USING ZVE7TST, R0            Low core addressability
		00000140	00000000	112	
				113	SV0LDPSW EQU    ZVE7TST+X' 140'            z/Arch Supervisor call old PSW
00000000		00000000	000001A0	115	ORG    ZVE7TST+X' 1A0'            z/Architecture RESTART PSW
000001A0	00000001 80000000			116	DC     X' 0000000180000000'
000001A8	00000000 00000200			117	DC     AD(BEGIN)
000001B0		000001B0	000001D0	119	ORG    ZVE7TST+X' 1D0'            z/Architecture PROGRAM CHECK PSW
000001D0	00020001 80000000			120	DC     X' 0002000180000000'
000001D8	00000000 0000DEAD			121	DC     AD(X' DEAD' )
000001E0		000001E0	00000200	123	ORG    ZVE7TST+X' 200'            Start of actual test program..
				125	*****
				126	*            The actual "ZVE7TST" program itself...
				127	*****
				128	*            Architecture Mode: z/Arch
				129	*            Register Usage:
				130	*            Register Usage:
				131	*            R0            (work)
				132	*            R1- 4        (work)
				133	*            R5            Testing control table - current test base
				134	*            R6- R7        (work)
				135	*            R8            First base register
				136	*            R9            Second base register
				137	*            R10          Third base register
				138	*            R11          E7TEST call return
				139	*            R12          E7TESTS register
				140	*            R13          (work)
				141	*            R14          Subroutine call
				142	*            R15          Secondary Subroutine call or work
				143	*            R15          Secondary Subroutine call or work
				144	*            R15          Secondary Subroutine call or work
				145	*****
00000200		00000200		147	USING    BEGIN, R8            FIRST Base Register
00000200		00001200		148	USING    BEGIN+4096, R9        SECOND Base Register
00000200		00002200		149	USING    BEGIN+8192, R10       THIRD Base Register
00000200	0580			151	BEGIN    BALR    R8, 0            Initalize FIRST base register
00000202	0680			152	BCTR    R8, 0            Initalize FIRST base register
00000204	0680			153	BCTR    R8, 0            Initalize FIRST base register
00000206	4190 8800		00000800	155	LA      R9, 2048(, R8)        Initalize SECOND base register
0000020A	4190 9800		00000800	156	LA      R9, 2048(, R9)        Initalize SECOND base register
				157	





[illegible]















LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				408	*****
				409	*            E7TEST DSECT
				410	*****
				412	E7TEST    DSECT ,
00000000	00000000			413	TSUB       DC     A(0)            pointer to test
00000004	0000			414	TNUM       DC     H' 00'           Test Number
00000006	00			415	DC     X' 00'
00000007	00			416	M4           DC     HL1' 00'           m4 used
				417	
00000008	40404040	40404040		418	OPNAME     DC     CL8' '           E6 name
00000010	00000000			419	V2ADDR     DC     A(0)           address of v2 source
00000014	00000000			420	V3ADDR     DC     A(0)           address of v3 source
00000018	00000000			421	RELEN       DC     A(0)           RESULT LENGTH
0000001C	00000000			422	READRR     DC     A(0)           result (expected) address
00000020	00000000	00000000		423	DS     FD                   gap
00000028	00000000	00000000		424	V10OUTPUT DS     XL16           V1 Output
00000038	00000000	00000000		425	DS     FD                   gap
				426	
				427	*            test routine will be here (from VRR-c macro)
				428	*
				429	*            followed by
				430	*            EXPECTED RESULT
				432	ZVE7TST    CSECT ,
000010B4		00000000	0000181F	433	DS     0F
				435	*****
				436	*            Macros to help build test tables
				437	*****
				439	*
				440	*    macro to generate individual test
				441	*
				442	MACRO
				443	VRR_C &INST, &M4
				444	. *                                    &INST    - VRR-c instruction under test
				445	. *                                    &m4       - m3 field
				446	
				447	GBLA   &TNUM
				448	&TNUM       SETA   &TNUM+1
				449	
				450	DS     0FD
				451	USING *, R5               base for test data and test routine
				452	
				453	T&TNUM     DC     A(X&TNUM)           address of test routine
				454	DC     H' &TNUM           test number
				455	DC     X' 00'
				456	DC     HL1' &M4'           m4
				457	DC     CL8' &INST'       instruction name
				458	DC     A(RE&TNUM+16)      address of v2 source



LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				507 *****
				508 * E6 VRR-c tests
				509 *****
				510 PRINT DATA
				511
				512 * E7B4 VGFM - VECTOR GALOIS FIELD MULTIPLY SUM
				513
				514 * VRR-c instruction, m4
				515 * followed by
				516 * 16 byte expected result (V1)
				517 * 16 byte V2 source
				518 * 16 byte V3 source
				519 * -----
				520 * VGFM - VECTOR GALOIS FIELD MULTIPLY SUM
				521 * -----
				522 * -----
				523 * case 0 - simple, simple debug
				524 * -----
				525 * Byte
				526 VRR_C VGFM, 0
000010B8				527+ DS OFD
000010B8		000010B8		528+ USING *, R5
000010B8	000010F8			529+T1 DC A(X1)
000010BC	0001			530+ DC H' 1'
000010BE	00			531+ DC X' 00'
000010BF	00			532+ DC HL1' 0'
000010C0	E5C7C6D4 40404040			533+ DC CL8' VGFM
000010C8	00001130			534+ DC A(RE1+16)
000010CC	00001140			535+ DC A(RE1+32)
000010D0	00000010			536+ DC A(16)
000010D4	00001120			537+REA1 DC A(RE1)
000010D8	00000000 00000000			538+ DS FD
000010E0	00000000 00000000			539+V101 DS XL16
000010E8	00000000 00000000			
000010F0	00000000 00000000			540+ DS FD
				541+*
000010F8				542+X1 DS OF
000010F8	E310 5010 0014	00000010		543+ LGF R1, V2ADDR
000010FE	E761 0000 0806	00000000		544+ VL v22, 0(R1)
00001104	E310 5014 0014	00000014		545+ LGF R1, V3ADDR
0000110A	E771 0000 0806	00000000		546+ VL v23, 0(R1)
00001110	E766 7000 0EB4			547+ VGFM V22, V22, V23, 0
00001116	E760 5028 080E	000010E0		548+ VST V22, V101
0000111C	07FB			549+ BR R11
00001120				550+RE1 DC OF
00001120				551+ DROP R5
00001120	01000080 00000000			552 DC XL16' 01000080000000000000000000000000' expected result
00001128	00000000 00000000			
00001130	80008080 00000000			553 DC XL16' 80008080000000000000000000000000' v2
00001138	00000000 00000000			
00001140	02000203 00000000			554 DC XL16' 02000203000000000000000000000000' v3
00001148	00000000 00000000			
				555
				556 * Halfword
				557 VRR_C VGFM, 1
00001150				558+ DS OFD

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001150		00001150		559+	USING *, R5	base for test data and test routine
00001150	00001190			560+T2	DC A(X2)	address of test routine
00001154	0002			561+	DC H' 2'	test number
00001156	00			562+	DC X' 00'	
00001157	01			563+	DC HL1' 1'	m4
00001158	E5C7C6D4 40404040			564+	DC CL8' VGFM	instruction name
00001160	000011C8			565+	DC A(RE2+16)	address of v2 source
00001164	000011D8			566+	DC A(RE2+32)	address of v3 source
00001168	00000010			567+	DC A(16)	result length
0000116C	000011B8			568+REA2	DC A(RE2)	result address
00001170	00000000 00000000			569+	DS FD	gap
00001178	00000000 00000000			570+V102	DS XL16	V1 output
00001180	00000000 00000000					
00001188	00000000 00000000			571+	DS FD	gap
				572+*		
00001190				573+X2	DS OF	
00001190	E310 5010 0014	00000010		574+	LGF R1, V2ADDR	load v2 source
00001196	E761 0000 0806	00000000		575+	VL v22, 0(R1)	use v22 to test decoder
0000119C	E310 5014 0014	00000014		576+	LGF R1, V3ADDR	load v3 source
000011A2	E771 0000 0806	00000000		577+	VL v23, 0(R1)	use v23 to test decoder
000011A8	E766 7000 1EB4			578+	VGFM V22, V22, V23, 1	test instruction (dest is a source)
000011AE	E760 5028 080E	00001178		579+	VST V22, V102	save v1 output
000011B4	07FB			580+	BR R11	return
000011B8				581+RE2	DC OF	xl16 expected result
000011B8				582+	DROP R5	
000011B8	00010000 00000000			583	DC XL16' 00010000000000000000000000000000'	expected result
000011C0	00000000 00000000					
000011C8	80000000 00000000			584	DC XL16' 80000000000000000000000000000000'	v2
000011D0	00000000 00000000					
000011D8	00020000 00000000			585	DC XL16' 00020000000000000000000000000000'	v3
000011E0	00000000 00000000					
				586		
				587 * Word		
				588	VRR_C VGFM, 2	
000011E8				589+	DS OFD	
000011E8		000011E8		590+	USING *, R5	base for test data and test routine
000011E8	00001228			591+T3	DC A(X3)	address of test routine
000011EC	0003			592+	DC H' 3'	test number
000011EE	00			593+	DC X' 00'	
000011EF	02			594+	DC HL1' 2'	m4
000011F0	E5C7C6D4 40404040			595+	DC CL8' VGFM	instruction name
000011F8	00001260			596+	DC A(RE3+16)	address of v2 source
000011FC	00001270			597+	DC A(RE3+32)	address of v3 source
00001200	00000010			598+	DC A(16)	result length
00001204	00001250			599+REA3	DC A(RE3)	result address
00001208	00000000 00000000			600+	DS FD	gap
00001210	00000000 00000000			601+V103	DS XL16	V1 output
00001218	00000000 00000000					
00001220	00000000 00000000			602+	DS FD	gap
				603+*		
00001228				604+X3	DS OF	
00001228	E310 5010 0014	00000010		605+	LGF R1, V2ADDR	load v2 source
0000122E	E761 0000 0806	00000000		606+	VL v22, 0(R1)	use v22 to test decoder
00001234	E310 5014 0014	00000014		607+	LGF R1, V3ADDR	load v3 source
0000123A	E771 0000 0806	00000000		608+	VL v23, 0(R1)	use v23 to test decoder
00001240	E766 7000 2EB4			609+	VGFM V22, V22, V23, 2	test instruction (dest is a source)



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001246	E760 9010 080E		00001210	610+	VST	V22, V103	save v1 output
0000124C	07FB			611+	BR	R11	return
00001250				612+RE3	DC	0F	xl16 expected result
00001250				613+	DROP	R5	
00001250	00000001 00000000			614	DC	XL16' 00000001000000000000000000000000'	expected result
00001258	00000000 00000000						
00001260	80000000 00000000			615	DC	XL16' 80000000000000000000000000000000'	v2
00001268	00000000 00000000						
00001270	00000002 00000000			616	DC	XL16' 00000002000000000000000000000000'	v3
00001278	00000000 00000000						
				617			
				618	* Doubleword		
				619	VRR_C	VGFM, 3	
00001280				620+	DS	0FD	
00001280		00001280		621+	USING	*, R5	base for test data and test routine
00001280	000012C0			622+T4	DC	A(X4)	address of test routine
00001284	0004			623+	DC	H' 4'	test number
00001286	00			624+	DC	X' 00'	
00001287	03			625+	DC	HL1' 3'	m4
00001288	E5C7C6D4 40404040			626+	DC	CL8' VGFM	instruction name
00001290	000012F8			627+	DC	A(RE4+16)	address of v2 source
00001294	00001308			628+	DC	A(RE4+32)	address of v3 source
00001298	00000010			629+	DC	A(16)	result length
0000129C	000012E8			630+REA4	DC	A(RE4)	result address
000012A0	00000000 00000000			631+	DS	FD	gap
000012A8	00000000 00000000			632+V104	DS	XL16	V1 output
000012B0	00000000 00000000						
000012B8	00000000 00000000			633+	DS	FD	gap
				634+*			
000012C0				635+X4	DS	0F	
000012C0	E310 5010 0014		00000010	636+	LGF	R1, V2ADDR	load v2 source
000012C6	E761 0000 0806		00000000	637+	VL	v22, 0(R1)	use v22 to test decoder
000012CC	E310 5014 0014		00000014	638+	LGF	R1, V3ADDR	load v3 source
000012D2	E771 0000 0806		00000000	639+	VL	v23, 0(R1)	use v23 to test decoder
000012D8	E766 7000 3EB4			640+	VGFM	V22, V22, V23, 3	test instruction (dest is a source)
000012DE	E760 5028 080E		000012A8	641+	VST	V22, V104	save v1 output
000012E4	07FB			642+	BR	R11	return
000012E8				643+RE4	DC	0F	xl16 expected result
000012E8				644+	DROP	R5	
000012E8	00000000 00000001			645	DC	XL16' 00000000000000001000000000000000'	expected result
000012F0	00000000 00000000						
000012F8	80000000 00000000			646	DC	XL16' 80000000000000000000000000000000'	v2
00001300	00000000 00000000						
00001308	00000000 00000002			647	DC	XL16' 00000000000000002000000000000000'	v3
00001310	00000000 00000000						
				648	* -----		
				649	* case 1		
				650	* -----		
				651	* Byte		
				652	VRR_C	VGFM, 0	
00001318				653+	DS	0FD	
00001318		00001318		654+	USING	*, R5	base for test data and test routine
00001318	00001358			655+T5	DC	A(X5)	address of test routine
0000131C	0005			656+	DC	H' 5'	test number
0000131E	00			657+	DC	X' 00'	
0000131F	00			658+	DC	HL1' 0'	m4

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001320	E5C7C6D4 40404040			659+	DC	CL8' VGFM	instruction name
00001328	00001390			660+	DC	A(RE5+16)	address of v2 source
0000132C	000013A0			661+	DC	A(RE5+32)	address of v3 source
00001330	00000010			662+	DC	A(16)	result length
00001334	00001380			663+REA5	DC	A(RE5)	result address
00001338	00000000 00000000			664+	DS	FD	gap
00001340	00000000 00000000			665+V105	DS	XL16	V1 output
00001348	00000000 00000000						
00001350	00000000 00000000			666+	DS	FD	gap
				667+*			
00001358				668+X5	DS	0F	
00001358	E310 5010 0014		00000010	669+	LGF	R1, V2ADDR	load v2 source
0000135E	E761 0000 0806		00000000	670+	VL	v22, 0(R1)	use v22 to test decoder
00001364	E310 5014 0014		00000014	671+	LGF	R1, V3ADDR	load v3 source
0000136A	E771 0000 0806		00000000	672+	VL	v23, 0(R1)	use v23 to test decoder
00001370	E766 7000 0EB4			673+	VGFM	V22, V22, V23, 0	test instruction (dest is a source)
00001376	E760 5028 080E		00001340	674+	VST	V22, V105	save v1 output
0000137C	07FB			675+	BR	R11	return
00001380				676+RE5	DC	0F	xl16 expected result
00001380				677+	DROP	R5	
00001380	28310031 00310031			678	DC	XL16' 28310031003100310031003100310031'	expected result
00001388	00310031 00310031						
00001390	50515253 54555657			679	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
00001398	58595A5B 5C5D5E5F						
000013A0	E0616263 64656667			680	DC	XL16' E06162636465666768696A6B6C6D6E6F'	v3
000013A8	68696A6B 6C6D6E6F						
				681			
				682 * Hal fword			
				683	VRR_C	VGFM, 1	
000013B0				684+	DS	0FD	
000013B0		000013B0		685+	USING	*, R5	base for test data and test routine
000013B0	000013F0			686+T6	DC	A(X6)	address of test routine
000013B4	0006			687+	DC	H' 6'	test number
000013B6	00			688+	DC	X' 00'	
000013B7	01			689+	DC	HL1' 1'	m4
000013B8	E5C7C6D4 40404040			690+	DC	CL8' VGFM	instruction name
000013C0	00001428			691+	DC	A(RE6+16)	address of v2 source
000013C4	00001438			692+	DC	A(RE6+32)	address of v3 source
000013C8	00000010			693+	DC	A(16)	result length
000013CC	00001418			694+REA6	DC	A(RE6)	result address
000013D0	00000000 00000000			695+	DS	FD	gap
000013D8	00000000 00000000			696+V106	DS	XL16	V1 output
000013E0	00000000 00000000						
000013E8	00000000 00000000			697+	DS	FD	gap
				698+*			
000013F0				699+X6	DS	0F	
000013F0	E310 5010 0014		00000010	700+	LGF	R1, V2ADDR	load v2 source
000013F6	E761 0000 0806		00000000	701+	VL	v22, 0(R1)	use v22 to test decoder
000013FC	E310 5014 0014		00000014	702+	LGF	R1, V3ADDR	load v3 source
00001402	E771 0000 0806		00000000	703+	VL	v23, 0(R1)	use v23 to test decoder
00001408	E766 7000 1EB4			704+	VGFM	V22, V22, V23, 1	test instruction (dest is a source)
0000140E	E760 5028 080E		000013D8	705+	VST	V22, V106	save v1 output
00001414	07FB			706+	BR	R11	return
00001418				707+RE6	DC	0F	xl16 expected result
00001418				708+	DROP	R5	
00001418	284C8064 00640064			709	DC	XL16' 284C8064006400640064006400640064'	expected result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001420	00640064 00640064						
00001428	50515253 54555657			710	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
00001430	58595A5B 5C5D5E5F						
00001438	E0616263 64656667			711	DC	XL16' E06162636465666768696A6B6C6D6E6F'	v3
00001440	68696A6B 6C6D6E6F						
				712			
				713	* Word		
				714	VRR_C VGFM, 2		
00001448				715+	DS	0FD	
00001448		00001448		716+	USING	*, R5	base for test data and test routine
00001448	00001488			717+T7	DC	A(X7)	address of test routine
0000144C	0007			718+	DC	H' 7'	test number
0000144E	00			719+	DC	X' 00'	
0000144F	02			720+	DC	HL1' 2'	m4
00001450	E5C7C6D4 40404040			721+	DC	CL8' VGFM	instruction name
00001458	000014C0			722+	DC	A(RE7+16)	address of v2 source
0000145C	000014D0			723+	DC	A(RE7+32)	address of v3 source
00001460	00000010			724+	DC	A(16)	result length
00001464	000014B0			725+REA7	DC	A(RE7)	result address
00001468	00000000 00000000			726+	DS	FD	gap
00001470	00000000 00000000			727+V107	DS	XL16	V1 output
00001478	00000000 00000000						
00001480	00000000 00000000			728+	DS	FD	gap
				729+*			
00001488				730+X7	DS	0F	
00001488	E310 5010 0014		00000010	731+	LGF	R1, V2ADDR	load v2 source
0000148E	E761 0000 0806		00000000	732+	VL	v22, 0(R1)	use v22 to test decoder
00001494	E310 5014 0014		00000014	733+	LGF	R1, V3ADDR	load v3 source
0000149A	E771 0000 0806		00000000	734+	VL	v23, 0(R1)	use v23 to test decoder
000014A0	E766 7000 2EB4			735+	VGFM	V22, V22, V23, 2	test instruction (dest is a source)
000014A6	E760 5028 080E		00001470	736+	VST	V22, V107	save v1 output
000014AC	07FB			737+	BR	R11	return
000014B0				738+RE7	DC	0F	xl16 expected result
000014B0				739+	DROP	R5	
000014B0	28F8A9F9 80D000D0			740	DC	XL16' 28F8A9F980D000D000D000D000D000D0'	expected result
000014B8	00D000D0 00D000D0						
000014C0	50515253 54555657			741	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
000014C8	58595A5B 5C5D5E5F						
000014D0	E0616263 64656667			742	DC	XL16' E06162636465666768696A6B6C6D6E6F'	v3
000014D8	68696A6B 6C6D6E6F						
				743			
				744	* Doubleword		
				745	VRR_C VGFM, 3		
000014E0				746+	DS	0FD	
000014E0		000014E0		747+	USING	*, R5	base for test data and test routine
000014E0	00001520			748+T8	DC	A(X8)	address of test routine
000014E4	0008			749+	DC	H' 8'	test number
000014E6	00			750+	DC	X' 00'	
000014E7	03			751+	DC	HL1' 3'	m4
000014E8	E5C7C6D4 40404040			752+	DC	CL8' VGFM	instruction name
000014F0	00001558			753+	DC	A(RE8+16)	address of v2 source
000014F4	00001568			754+	DC	A(RE8+32)	address of v3 source
000014F8	00000010			755+	DC	A(16)	result length
000014FC	00001548			756+REA8	DC	A(RE8)	result address
00001500	00000000 00000000			757+	DS	FD	gap
00001508	00000000 00000000			758+V108	DS	XL16	V1 output

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001510	00000000 00000000						
00001518	00000000 00000000			759+	DS	FD	gap
				760+*			
00001520				761+X8	DS	0F	
00001520	E310 5010 0014		00000010	762+	LGF	R1, V2ADDR	load v2 source
00001526	E761 0000 0806		00000000	763+	VL	v22, 0(R1)	use v22 to test decoder
0000152C	E310 5014 0014		00000014	764+	LGF	R1, V3ADDR	load v3 source
00001532	E771 0000 0806		00000000	765+	VL	v23, 0(R1)	use v23 to test decoder
00001538	E766 7000 3EB4			766+	VGFM	V22, V22, V23, 3	test instruction (dest is a source)
0000153E	E760 5028 080E		00001508	767+	VST	V22, V108	save v1 output
00001544	07FB			768+	BR	R11	return
00001548				769+RE8	DC	0F	xl16 expected result
00001548				770+	DROP	R5	
00001548	29E8A8E9 ABEAAAEB			771	DC	XL16' 29E8A8E9ABEAAAEB81C001C001C001C0'	expected result
00001550	81C001C0 01C001C0						
00001558	50515253 54555657			772	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
00001560	58595A5B 5C5D5E5F						
00001568	E0616263 64656667			773	DC	XL16' E06162636465666768696A6B6C6D6E6F'	v3
00001570	68696A6B 6C6D6E6F						
				774			
				775 *			
				776 * case 2			
				777 *			
				778 * Byte			
				779	VRR_C	VGFM, 0	
00001578				780+	DS	0FD	
00001578		00001578		781+	USING	*, R5	base for test data and test routine
00001578	000015B8			782+T9	DC	A(X9)	address of test routine
0000157C	0009			783+	DC	H' 9'	test number
0000157E	00			784+	DC	X' 00'	
0000157F	00			785+	DC	HL1' 0'	m4
00001580	E5C7C6D4 40404040			786+	DC	CL8' VGFM	instruction name
00001588	000015F0			787+	DC	A(RE9+16)	address of v2 source
0000158C	00001600			788+	DC	A(RE9+32)	address of v3 source
00001590	00000010			789+	DC	A(16)	result length
00001594	000015E0			790+REA9	DC	A(RE9)	result address
00001598	00000000 00000000			791+	DS	FD	gap
000015A0	00000000 00000000			792+V109	DS	XL16	V1 output
000015A8	00000000 00000000						
000015B0	00000000 00000000			793+	DS	FD	gap
				794+*			
000015B8				795+X9	DS	0F	
000015B8	E310 5010 0014		00000010	796+	LGF	R1, V2ADDR	load v2 source
000015BE	E761 0000 0806		00000000	797+	VL	v22, 0(R1)	use v22 to test decoder
000015C4	E310 5014 0014		00000014	798+	LGF	R1, V3ADDR	load v3 source
000015CA	E771 0000 0806		00000000	799+	VL	v23, 0(R1)	use v23 to test decoder
000015D0	E766 7000 0EB4			800+	VGFM	V22, V22, V23, 0	test instruction (dest is a source)
000015D6	E760 5028 080E		000015A0	801+	VST	V22, V109	save v1 output
000015DC	07FB			802+	BR	R11	return
000015E0				803+RE9	DC	0F	xl16 expected result
000015E0				804+	DROP	R5	
000015E0	05E605E6 05E605E6			805	DC	XL16' 05E605E605E605E605E605E6071E'	expected result
000015E8	05E605E6 05E6071E						
000015F0	50515253 54555657			806	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
000015F8	58595A5B 5C5D5E5F						
00001600	F6E6D6C6 B6A69686			807	DC	XL16' F6E6D6C6B6A69686766656463626160E'	v3



LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001608	76665646 3626160E			808		
				809 * Halfword		
				810	VRR_C VGFM, 1	
00001610				811+	DS OFD	
00001610		00001610		812+	USING *, R5	base for test data and test routine
00001610	00001650			813+T10	DC A(X10)	address of test routine
00001614	000A			814+	DC H' 10'	test number
00001616	00			815+	DC X' 00'	
00001617	01			816+	DC HL1' 1'	m4
00001618	E5C7C6D4 40404040			817+	DC CL8' VGFM	instruction name
00001620	00001688			818+	DC A(RE10+16)	address of v2 source
00001624	00001698			819+	DC A(RE10+32)	address of v3 source
00001628	00000010			820+	DC A(16)	result length
0000162C	00001678			821+REA10	DC A(RE10)	result address
00001630	00000000 00000000			822+	DS FD	gap
00001638	00000000 00000000			823+V1010	DS XL16	V1 output
00001640	00000000 00000000					
00001648	00000000 00000000			824+	DS FD	gap
				825+*		
00001650				826+X10	DS OF	
00001650	E310 5010 0014		00000010	827+	LGF R1, V2ADDR	load v2 source
00001656	E761 0000 0806		00000000	828+	VL v22, 0(R1)	use v22 to test decoder
0000165C	E310 5014 0014		00000014	829+	LGF R1, V3ADDR	load v3 source
00001662	E771 0000 0806		00000000	830+	VL v23, 0(R1)	use v23 to test decoder
00001668	E766 7000 1EB4			831+	VGFM V22, V22, V23, 1	test instruction (dest is a source)
0000166E	E760 5028 080E		00001638	832+	VST V22, V1010	save v1 output
00001674	07FB			833+	BR R11	return
00001678				834+RE10	DC OF	xl16 expected result
00001678				835+	DROP R5	
00001678	OBACOBAC OBACOBAC			836	DC XL16' OBACOBACOBACOBACOBACOBACOBACOBACBAEF954'	expected result
00001680	OBACOBAC OBACOBAC					
00001688	50515253 54555657			837	DC XL16' 505152535455565758595A5B5C5D5E5F'	v2
00001690	58595A5B 5C5D5E5F					
00001698	F6E6D6C6 B6A69686			838	DC XL16' F6E6D6C6B6A69686766656463626160E'	v3
000016A0	76665646 3626160E					
				839		
				840 * Word		
				841	VRR_C VGFM, 2	
000016A8				842+	DS OFD	
000016A8		000016A8		843+	USING *, R5	base for test data and test routine
000016A8	000016E8			844+T11	DC A(X11)	address of test routine
000016AC	000B			845+	DC H' 11'	test number
000016AE	00			846+	DC X' 00'	
000016AF	02			847+	DC HL1' 2'	m4
000016B0	E5C7C6D4 40404040			848+	DC CL8' VGFM	instruction name
000016B8	00001720			849+	DC A(RE11+16)	address of v2 source
000016BC	00001730			850+	DC A(RE11+32)	address of v3 source
000016C0	00000010			851+	DC A(16)	result length
000016C4	00001710			852+REA11	DC A(RE11)	result address
000016C8	00000000 00000000			853+	DS FD	gap
000016D0	00000000 00000000			854+V1011	DS XL16	V1 output
000016D8	00000000 00000000					
000016E0	00000000 00000000			855+	DS FD	gap
				856+*		
000016E8				857+X11	DS OF	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016E8	E310 5010 0014		00000010	858+	LGF	R1, V2ADDR	load v2 source
000016EE	E761 0000 0806		00000000	859+	VL	v22, 0(R1)	use v22 to test decoder
000016F4	E310 5014 0014		00000014	860+	LGF	R1, V3ADDR	load v3 source
000016FA	E771 0000 0806		00000000	861+	VL	v23, 0(R1)	use v23 to test decoder
00001700	E766 7000 2EB4			862+	VGFM	V22, V22, V23, 2	test instruction (dest is a source)
00001706	E760 5028 080E		000016D0	863+	VST	V22, V1011	save v1 output
0000170C	07FB			864+	BR	R11	return
00001710				865+RE11	DC	0F	xl16 expected result
00001710				866+	DROP	R5	
00001710	16D816D8 16D816D8			867	DC	XL16' 16D816D816D816D816D816DAF432E420'	expected result
00001718	16D816DA F432E420						
00001720	50515253 54555657			868	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
00001728	58595A5B 5C5D5E5F						
00001730	F6E6D6C6 B6A69686			869	DC	XL16' F6E6D6C6B6A69686766656463626160E'	v3
00001738	76665646 3626160E						
				870			
				871	* Doubleword		
				872	VRR_C	VGFM, 3	
00001740				873+	DS	0FD	
00001740		00001740		874+	USING	*, R5	base for test data and test routine
00001740	00001780			875+T12	DC	A(X12)	address of test routine
00001744	000C			876+	DC	H' 12'	test number
00001746	00			877+	DC	X' 00'	
00001747	03			878+	DC	HL1' 3'	m4
00001748	E5C7C6D4 40404040			879+	DC	CL8' VGFM	instruction name
00001750	000017B8			880+	DC	A(RE12+16)	address of v2 source
00001754	000017C8			881+	DC	A(RE12+32)	address of v3 source
00001758	00000010			882+	DC	A(16)	result length
0000175C	000017A8			883+REA12	DC	A(RE12)	result address
00001760	00000000 00000000			884+	DS	FD	gap
00001768	00000000 00000000			885+V1012	DS	XL16	V1 output
00001770	00000000 00000000						
00001778	00000000 00000000			886+	DS	FD	gap
				887+*			
00001780				888+X12	DS	0F	
00001780	E310 5010 0014		00000010	889+	LGF	R1, V2ADDR	load v2 source
00001786	E761 0000 0806		00000000	890+	VL	v22, 0(R1)	use v22 to test decoder
0000178C	E310 5014 0014		00000014	891+	LGF	R1, V3ADDR	load v3 source
00001792	E771 0000 0806		00000000	892+	VL	v23, 0(R1)	use v23 to test decoder
00001798	E766 7000 3EB4			893+	VGFM	V22, V22, V23, 3	test instruction (dest is a source)
0000179E	E760 5028 080E		00001768	894+	VST	V22, V1012	save v1 output
000017A4	07FB			895+	BR	R11	return
000017A8				896+RE12	DC	0F	xl16 expected result
000017A8				897+	DROP	R5	
000017A8	2BB02BB0 2BB02BB2			898	DC	XL16' 2BB02BB02BB02BB2E97AF96AC95AD948'	expected result
000017B0	E97AF96A C95AD948						
000017B8	50515253 54555657			899	DC	XL16' 505152535455565758595A5B5C5D5E5F'	v2
000017C0	58595A5B 5C5D5E5F						
000017C8	F6E6D6C6 B6A69686			900	DC	XL16' F6E6D6C6B6A69686766656463626160E'	v3
000017D0	76665646 3626160E						
				901			
000017D8	00000000			902	DC	F' 0'	END OF TABLE
000017DC	00000000			903	DC	F' 0'	
				904	*		
				905	* table of pointers to individual load test		
				906	*		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
000017E0				907 E7TESTS	DS	OF		
				908	PTTABLE			
000017E0				909+TTABLE	DS	OF		
000017E0	000010B8			910+	DC	A(T1)	TEST &CUR	
000017E4	00001150			911+	DC	A(T2)	TEST &CUR	
000017E8	000011E8			912+	DC	A(T3)	TEST &CUR	
000017EC	00001280			913+	DC	A(T4)	TEST &CUR	
000017F0	00001318			914+	DC	A(T5)	TEST &CUR	
000017F4	000013B0			915+	DC	A(T6)	TEST &CUR	
000017F8	00001448			916+	DC	A(T7)	TEST &CUR	
000017FC	000014E0			917+	DC	A(T8)	TEST &CUR	
00001800	00001578			918+	DC	A(T9)	TEST &CUR	
00001804	00001610			919+	DC	A(T10)	TEST &CUR	
00001808	000016A8			920+	DC	A(T11)	TEST &CUR	
0000180C	00001740			921+	DC	A(T12)	TEST &CUR	
				922+*				
00001810	00000000			923+	DC	A(0)	END OF TABLE	
00001814	00000000			924+	DC	A(0)		
				925				
00001818	00000000			926	DC	F' 0'	END OF TABLE	
0000181C	00000000			927	DC	F' 0'		



LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				929	*****
				930	*            Register equates
				931	*****
		00000000	00000001	933 R0	EQU 0
		00000001	00000001	934 R1	EQU 1
		00000002	00000001	935 R2	EQU 2
		00000003	00000001	936 R3	EQU 3
		00000004	00000001	937 R4	EQU 4
		00000005	00000001	938 R5	EQU 5
		00000006	00000001	939 R6	EQU 6
		00000007	00000001	940 R7	EQU 7
		00000008	00000001	941 R8	EQU 8
		00000009	00000001	942 R9	EQU 9
		0000000A	00000001	943 R10	EQU 10
		0000000B	00000001	944 R11	EQU 11
		0000000C	00000001	945 R12	EQU 12
		0000000D	00000001	946 R13	EQU 13
		0000000E	00000001	947 R14	EQU 14
		0000000F	00000001	948 R15	EQU 15
				950	*****
				951	*            Register equates
				952	*****
		00000000	00000001	954 V0	EQU 0
		00000001	00000001	955 V1	EQU 1
		00000002	00000001	956 V2	EQU 2
		00000003	00000001	957 V3	EQU 3
		00000004	00000001	958 V4	EQU 4
		00000005	00000001	959 V5	EQU 5
		00000006	00000001	960 V6	EQU 6
		00000007	00000001	961 V7	EQU 7
		00000008	00000001	962 V8	EQU 8
		00000009	00000001	963 V9	EQU 9
		0000000A	00000001	964 V10	EQU 10
		0000000B	00000001	965 V11	EQU 11
		0000000C	00000001	966 V12	EQU 12
		0000000D	00000001	967 V13	EQU 13
		0000000E	00000001	968 V14	EQU 14
		0000000F	00000001	969 V15	EQU 15
		00000010	00000001	970 V16	EQU 16
		00000011	00000001	971 V17	EQU 17
		00000012	00000001	972 V18	EQU 18
		00000013	00000001	973 V19	EQU 19
		00000014	00000001	974 V20	EQU 20
		00000015	00000001	975 V21	EQU 21





SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES					
R8	U	00000008	1	941	147	151	152	153	155	
R9	U	00000009	1	942	148	155	156	158		
RE1	F	00001120	4	550	534	535	537			
RE10	F	00001678	4	834	818	819	821			
RE11	F	00001710	4	865	849	850	852			
RE12	F	000017A8	4	896	880	881	883			
RE2	F	000011B8	4	581	565	566	568			
RE3	F	00001250	4	612	596	597	599			
RE4	F	000012E8	4	643	627	628	630			
RE5	F	00001380	4	676	660	661	663			
RE6	F	00001418	4	707	691	692	694			
RE7	F	000014B0	4	738	722	723	725			
RE8	F	00001548	4	769	753	754	756			
RE9	F	000015E0	4	803	787	788	790			
REA1	A	000010D4	4	537						
REA10	A	0000162C	4	821						
REA11	A	000016C4	4	852						
REA12	A	0000175C	4	883						
REA2	A	0000116C	4	568						
REA3	A	00001204	4	599						
REA4	A	0000129C	4	630						
REA5	A	00001334	4	663						
REA6	A	000013CC	4	694						
REA7	A	00001464	4	725						
REA8	A	000014FC	4	756						
REA9	A	00001594	4	790						
READDR	A	0000001C	4	422	219					
REG2LOW	U	000000DD	1	365						
REG2PATT	U	AABBCCDD	1	364						
RELEN	A	00000018	4	421						
RPTDWSAV	D	00000398	8	290	277	281				
RPTERROR	I	0000032C	4	257	232					
RPTSAVE	F	00000390	4	287	257	284				
RPTSVR5	F	00000394	4	288	258	283				
SKL0001	U	0000004E	1	177	193					
SKT0001	C	0000022A	20	174	177	194				
SVOLDPSW	U	00000140	0	113						
T1	A	000010B8	4	529	910					
T10	A	00001610	4	813	919					
T11	A	000016A8	4	844	920					
T12	A	00001740	4	875	921					
T2	A	00001150	4	560	911					
T3	A	000011E8	4	591	912					
T4	A	00001280	4	622	913					
T5	A	00001318	4	655	914					
T6	A	000013B0	4	686	915					
T7	A	00001448	4	717	916					
T8	A	000014E0	4	748	917					
T9	A	00001578	4	782	918					
TESTING	F	00001004	4	376	213					
TNUM	H	00000004	2	414	212	260				
TSUB	A	00000000	4	413	216					
TTABLE	F	000017E0	4	909						
V0	U	00000000	1	954						
V1	U	00000001	1	955	215					
V10	U	0000000A	1	964						









DESC	SYMBOL	SIZE	POS	ADDR
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**Entry: 0**

Image	IMAGE	6176	0000- 181F	0000- 181F
Regi on		6176	0000- 181F	0000- 181F
CSECT	ZVE7TST	6176	0000- 181F	0000- 181F

STMT	FILE NAME
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1 /home/tn529/sharedvfp/tests/zvector-e7-02-VGFM asm
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**\*\* NO ERRORS FOUND \*\***